MOSFET – Power, N-Channel, SUPERFET[®] III, Automotive, Easy-Drive 650 V, 65 A, 40 mΩ

NVHL040N65S3

Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advanced technology is tailored to minimize conduction loss, provides superior switching performance, and withstand extreme dv/dt rate.

Consequently, SUPERFET III MOSFET Easy drive series helps manage EMI issues and allows for easier design implementation.

Features

- AEC-Q101 Qualified
- 700 V @ T_J = 150°C
- Typ. R_{DS(on)} = 35.4 mΩ
- Ultra Low Gate Charge (Typ. Q_g = 136 nC)
- Low Effective Output Capacitance (Typ. C_{oss(eff.)} = 1154 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

Applications

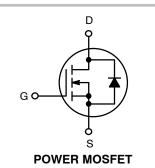
- Automotive On Board Charger
- Automotive DC/DC Converter for HEV



ON Semiconductor®

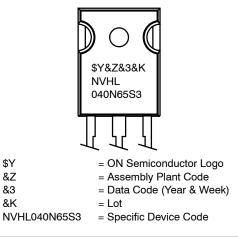
www.onsemi.com

V _{DSS}	R _{DS(ON)} MAX	I _D MAX
650 V	40 m Ω @ 10 V	65 A





MARKING DIAGRAM



ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

Symbol	Parameter	Value	Unit V		
V _{DSS}	Drain to Source Voltage	650			
V _{GSS}	Gate to Source Voltage	– DC	±30	V	
		– AC (f > 1 Hz)	±30		
ID	Drain Current	– Continuous (T _C = 25°C)	65	А	
		– Continuous (T _C = 100°C)	41		
I _{DM}	Drain Current - Pulsed (Note 1)		162.5	А	
E _{AS}	Single Pulsed Avalanche Energy (Note 2)		358	mJ	
I _{AS}	Avalanche Current (Note 2)		8.1	А	
E _{AR}	Repetitive Avalanche Energy (Note 1)		4.17	mJ	
dv/dt	MOSFET dv/dt		100	V/ns	
	Peak Diode Recovery dv/dt (Note 3)		20		
P _D	Power Dissipation	(T _C = 25°C)	417	W	
		- Derate Above 25°C	3.33	W/°C	
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +150	°C	
ΤL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 seconds		300	°C	

ABSOLUTE MAXIMUM RATINGS (T_C = 25°C, Unless otherwise noted)

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive rating: pulse width limited by maximum junction temperature. 2. $I_{AS} = 8.1 \text{ A}, R_G = 25 \Omega$, starting $T_J = 25^{\circ}C$. 3. $I_{SD} \leq 32.5 \text{ A}, \text{ di/dt} \leq 200 \text{ A/}\mu\text{s}, V_{DD} \leq 400 \text{ V}, \text{ starting } T_J = 25^{\circ}C$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction to Case, Max.	0.3	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	40	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Packing Method	Reel Size	Tape Width	Quantity
NVHL040N65S3	NVHL040N65S3	TO-247 G03	Tube	N/A	N/A	30 Units

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
Symbol	Falametei	Test conditions	WIIII	тур	WIGA	Unit
OFF CHARACT	ERISTICS					
BV _{DSS}	Drain to Source Breakdown Voltage	V_{GS} = 0 V, I_D = 1 mA, T_J = 25°C	650	-	-	V
		V_{GS} = 0 V, I_D = 1 mA, T_J = 150°C	700	-	-	V
$\Delta \text{BV}_{\text{DSS}} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 1$ mA, Referenced to 25°C	-	0.64	-	V/°C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	1	μΑ
		$V_{DS} = 520 \text{ V}, \text{ T}_{C} = 125^{\circ}\text{C}$	-	4.5	-	
I _{GSS}	Gate to Body Leakage Current	V_{GS} = ±30 V, V_{DS} = 0 V	-	-	±100	nA
ON CHARACTE	RISTICS					
V _{GS(th)}	Gate Threshold Voltage	$V_{GS} = V_{DS}$, $I_D = 1.7$ mA	2.5	-	4.5	V
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10 V, I _D = 32.5 A	-	35.4	40	mΩ
9 FS	Forward Transconductance	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 32.5 \text{ A}$	-	46	-	S

ELECTRICAL CHARACTERISTICS ($T_C = 25^{\circ}C$ unless otherwise noted) (continued)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
YNAMIC CH	ARACTERISTICS	· · · · · ·				
C _{iss}	Input Capacitance	V_{DS} = 400 V, V_{GS} = 0 V, f = 1 MHz	-	4740	-	pF
C _{oss}	Output Capacitance		-	120	-	pF
C _{oss(eff.)}	Effective Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	1154	-	pF
C _{oss(er.)}	Energy Related Output Capacitance	V_{DS} = 0 V to 400 V, V_{GS} = 0 V	-	171	-	pF
Q _{g(tot)}	Total Gate Charge at 10 V	$V_{DS} = 400 \text{ V}, \text{ I}_{D} = 32.5 \text{ A}, \text{ V}_{GS} = 10 \text{ V}$	-	136	-	nC
Q _{gs}	Gate to Source Gate Charge	(Note 4)	-	33	-	nC
Q _{gd}	Gate to Drain "Miller" Charge		-	59	-	nC
ESR	Equivalent Series Resistance	f = 1 MHz	-	0.7	-	Ω
WITCHING C	HARACTERISTICS					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 400 \text{ V}, \text{ I}_{D} = 32.5 \text{ A},$	-	35	-	ns
t _r	Turn-On Rise Time	V _{GS} = 10 V, R _g = 3.3 Ω (Note 4)	-	51	-	ns
t _{d(off)}	Turn-Off Delay Time		-	95	-	ns
t _f	Turn-Off Fall Time		-	30	-	ns
OURCE-DRA	IN DIODE CHARACTERISTICS					-
۱ _S	Maximum Continuous Drain to Source Diode Forward Current		-	-	65	А
I _{SM}	Maximum Pulsed Drain to Source Diode Forward Current		-	-	162.5	Α
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 32.5 A	-	-	1.2	V
t _{rr}	Reverse Recovery Time	V _{GS} = 0 V, I _{SD} = 32.5 A, dI _F /dt = 100 A/µs	-	534	-	ns
Qrr	Reverse Recovery Charge		_	13.6	_	uС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions. 4. Essentially independent of operating temperature typical characteristics.

13.6

μC

Reverse Recovery Charge

Q_{rr}

TYPICAL PERFORMANCE CHARACTERISTICS

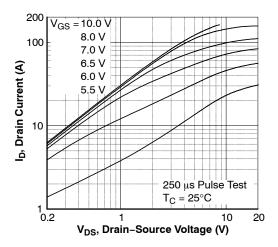


Figure 1. On–Region Characteristics 25°C

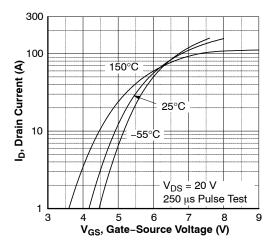
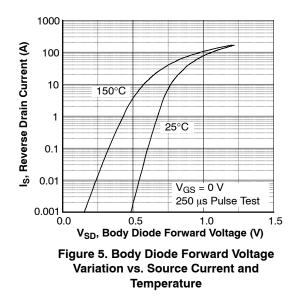


Figure 3. Transfer Characteristics



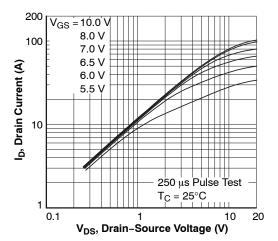


Figure 2. On–Region Characteristics 150°C

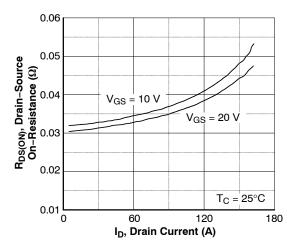
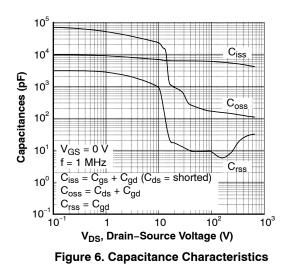


Figure 4. On-Resistance Variation vs. Drain Current and Gate Voltage



TYPICAL PERFORMANCE CHARACTERISTICS (continued)

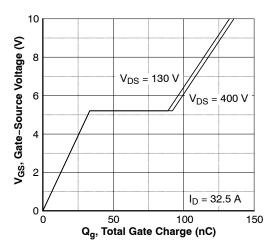


Figure 7. Gate Charge Characteristics

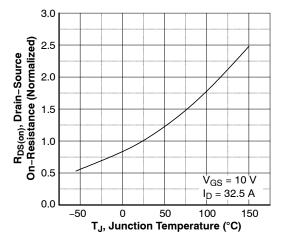


Figure 9. On–Resistance Variation vs. Temperature

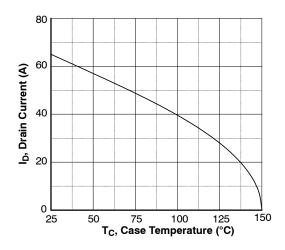


Figure 11. Maximum Drain Current vs. Case Temperature

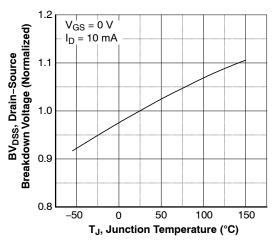


Figure 8. Breakdown Voltage Variation vs. Temperature

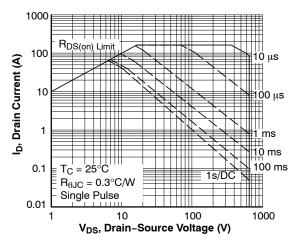


Figure 10. Maximum Safe Operating Area

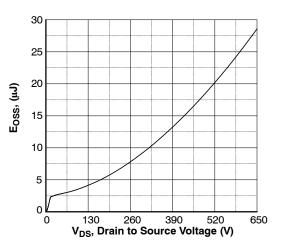
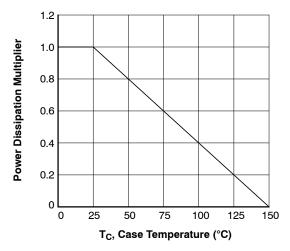


Figure 12. E_{OSS} vs. Drain to Source Voltage

TYPICAL PERFORMANCE CHARACTERISTICS (continued)





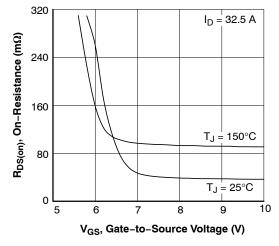


Figure 15. R_{DS(on)} vs. Gate Voltage Figure

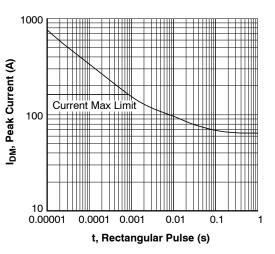


Figure 14. Peak Current Capability

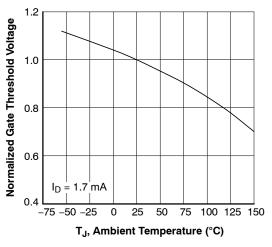


Figure 16. Normalized Gate Threshold Voltage vs. Temperature

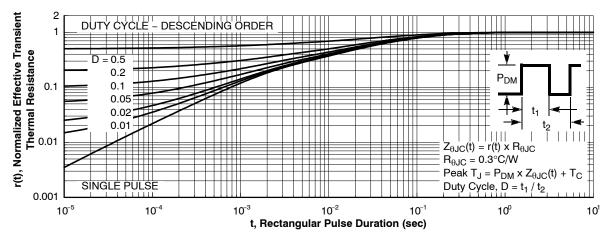
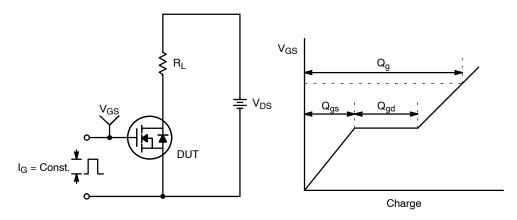


Figure 17. Transient Thermal Response Curve





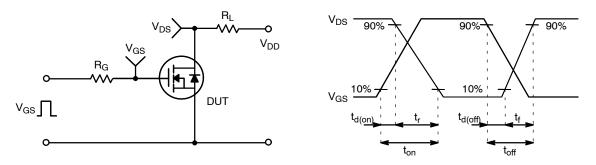
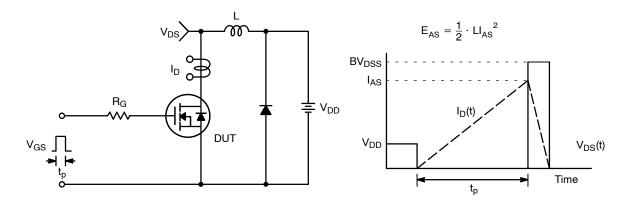


Figure 19. Resistive Switching Test Circuit & Waveforms





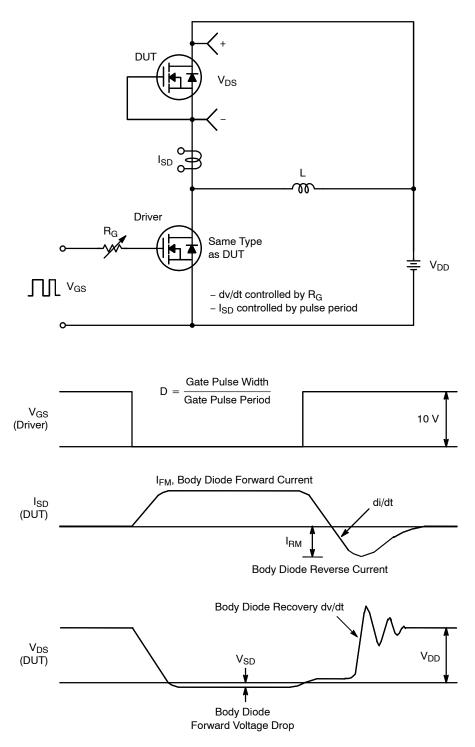


Figure 21. Peak Diode Recovery dv/dt Test Circuit & Waveforms

SUPERFET is a registered trademark of Semiconductor Components Industries, LLC (SCILLC) or its subsidiaries in the United States and/or other countries.



6.60 6.80 7.00 Electronic versions are uncontrolled except when accessed directly from the Document Repository. **DOCUMENT NUMBER:** 98AON93302G Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red. **DESCRIPTION:** TO-247-3LD PAGE 1 OF 1

not follow the Generic Marking.

ON Semiconductor and 💷 are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. ON Semiconductor does not convey any license under its patent rights nor the rights of others.

~

12.81

~

E1

ØP1



D2

ON Semiconductor

onsemi, ONSEMI, and other names, marks, and brands are registered and/or common law trademarks of Semiconductor Components Industries, LLC dba "onsemi" or its affiliates and/or subsidiaries in the United States and/or other countries. onsemi owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of onsemi's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. onsemi reserves the right to make changes at any time to any products or information herein, without notice. The information herein is provided "as-is" and onsemi makes no warranty, representation or guarantee regarding the accuracy of the information, product features, availability, functionality, or suitability of its products for any particular purpose, nor does **onsemi** assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using **onsemi** products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by **onsemi**. "Typical" parameters which may be provided in **onsemi** data sheets and/or specifications can and do vary in different applications and calcular performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. **onsemi** does not convey any license under any of its intellectual property rights nor the rights of others. **onsemi** products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use **onsemi** products for any such unintended or unauthorized application, Buyer shall indemnify and hold **onsemi** and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that **onsemi** was negligent regarding the design or manufacture of the part. **onsemi** is an Equal Opportunity/Affirmative Action Employer. This literature is subject to all applicable copyright laws and is not for resale in any manner.

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

TECHNICAL SUPPORT

onsemi Website: www.onsemi.com

Email Requests to: orderlit@onsemi.com

North American Technical Support: Voice Mail: 1 800-282-9855 Toll Free USA/Canada Phone: 011 421 33 790 2910

Europe, Middle East and Africa Technical Support: Phone: 00421 33 790 2910 For additional information, please contact your local Sales Representative